

L Number	Hits	Search Text	DB	Time stamp
1	1214	("fanout") and (test\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:06
2	2160	("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:29
4	37	((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:12
5	0	((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:29
3	14	((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:08
6	36	((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).clm.) not (((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).ab.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:12
7	52	((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))) and 714/724.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:29
8	7	((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).ab. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).ti. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).clm.) and 714/724.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:30
9	9	((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).ab. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).ti. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).clm.) and 714/726.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:30
10	0	((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).ab. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).ti. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).clm.) and 714/742.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:30
11	5	((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).ab. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).ti. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).clm.) and 714/738.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:30
12	0	((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).ab. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).ti. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop"))).clm.) and 714/739.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:31

13	0	((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop")).ab. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop")).ti. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop")).clm.) and 714/733.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:31
14	0	((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop")).ab. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop")).ti. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop")).clm.) and 714/728.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:31
15	1	((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop")).ab. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop")).ti. ((("fanout" "fan out") and (test\$3) and (latch\$3 register\$2 flipflop "flip-flop" "flip flop")).clm.) and 714/727.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:31
-	1403	((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 12:59
-	68	((((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 12:59
-	310	((((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays switch switches)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 11:56
-	60	(((((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays switch switches)) and ((clock clocks) with (latch "shift register" flip-flop flipflop register)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 16:21
-	885	714/704.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 12:00
-	0	(((((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays switch switches)) and ((clock clocks) with (latch "shift register" flip-flop flipflop register))) and (fan-out "fan out" fanout)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 12:06
-	1408020	DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 16:26

-	311	((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays switch switches)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:07
-	16361	(DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:13
-	25770	(DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test (circuit near test\$3)) and (test near (data signal input pattern source information))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:54
-	4957	"5" and (((relay relays relayed relaying switch switching switched switches) with circuit) and ((fanout "fan out" serial-to-parallel multiplex\$3) near (relay relays relayed relaying switch switching switched switches)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 14:45
-	1284	("5" and (((relay relays relayed relaying switch switching switched switches) with circuit) and ((fanout "fan out" serial-to-parallel multiplex\$3) near (relay relays relayed relaying switch switching switched switches))) ) and (latch and clock)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 14:47